Pulse and hold strategy for switching current m easurem ents

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We investigate by theory and experiment, the Josephson junction switching current detector in an environment with frequency dependent damping. A nalysis of the circuit's phase space show that a favorable topology for switching can be obtained with overdamped dynamics at high frequencies. A pulse-and-hold method is described, where a fast switch pulse brings the circuit close to an unstable point in the phase space when biased at the hold level. Experiments are performed on C ooper pair transistors and Q uantronium circuits, which are overdamped at high frequencies with an on-chip RC shunt. For 20 µs switch pulses the switching process is well described by thermal equilibrium escape, based on a generalization of K ram ers form ula to the case of frequency dependent damping. A capacitor bias method is used to create very rapid, 25 ns switch pulses, where it is observed that the switching process is not governed by thermal equilibrium noise.

I. IN TRODUCTION

A classical non-linear dynam ical system, when driven to a point of instability, will undergo a bifurcation, where the system evolves tow and distinctly di erent nalstates. At bifurcation the system becomes very sensitive and the smallest uctuation can determ ine the evolution of a massive system with huge potential energy. This property of in nite sensitivity at the point of instability can be used to amplify very weak signals, and has recently been the focus of investigation in the design of quantum detectors to readout the state of quantum bits (qubits) built from Josephson junction (JJ) circuits. Here we exam ine in experiment and theory a pulse and hold strategy for rapid switching of a JJ circuit which is quickly brought near a point of instability, pointing out several im portant properties for an ideal detector. W e focus on switching in a circuit with overdam ped phase dynam ics at high frequencies, and underdam ped at low frequencies. This HF-overdam ped case is relevant to experiments on sm all capacitance JJs biased with typical measurem ent leads.

C lassical JJs have strongly non-linear electrodynam ics and they have served as a model system in non-linear physics for the last 40 years. M ore recently it has been shown that JJ circuits with small capacitance can also exhibit quantum dynamics when properly measured at low enough tem peratures. Experim ental dem onstration of the macroscopic quantum dynamics in these circuits has relied on e cient quantum measurement strategies, characterized by high single shot sensitivity with rapid reset time and low back action. Some of these measurem ent or detection m ethods are based on the switching of a JJ circuit from the zero voltage state to a nite voltage state.^{1,2,3,4} O ther detection m ethods are based on a dispersive technique, where a high frequency signal probes the phase dynam ics of a qubit.^{5,6,7,8,9,10,11,12} These dispersive methods have achieved the desired sensitivity

at considerably higher speeds than the static switching m ethods, allowing individual quantum m easurements to be made with much higher duty cycle. In particular, the dispersive m ethods have shown that it is possible to continuously m onitor the qubit.¹³ However, for both static switching and dispersive m ethods, the sensitivity of the technique is in proved by exploiting the non-linear properties of the readout circuit in a pulse and hold m easurement strategy. This in proved sensitivity of the pulse and hold m ethod is not surprising, because when properly designed, the pulse and hold technique will exploit the in nite sensitivity of a non-linear system at the point of instability.

The general idea of exploiting the in nite sensitivity at an instable point is a recurrent them e in applications of non-linear dynamics. The basic idea has been used since the early days of microw ave engineering in the wellknown param etric am pli er¹⁴ which has in nite gain at the point of dynam ical instability. The unstable point can be conveniently represented as a saddle point for the phase space trajectories of the non-linear dynam ical system . In the pulse and hold m easurem ent m ethod an initial fast pulse is used to quickly bring the system to the saddle point for a particular hold bias level. The hold level is chosen so that the phase space topology favors a rapid separation in to the two basins of attraction in the phase space. The initial pulse should be not so fast that it will cause excessive back action on the qubit, but not so slow that it's duration exceeds the relaxation time of the qubit. The length of the hold pulse is that which is required to achieve a signal to noise ratio necessary for unambiguous determ ination of the resulting basin of attraction. In practice this length is set by the liters and ampliers in the second stage of the quantum measurem ent system .

In this paper we discuss pulse and hold detection in the context of switching from the zero voltage state to the nite voltage state of a JJ.W e give an overview of

such switching in JJs, focusing on the HF-overdam ped case. Switching detectors with overdam ped high frequency phase dynam ics are di erent from all other qubit m easurem ent strategies in plem ented thus far, where underdam ped phase dynam ics has been used. How ever, the HF-overdam ped case is quite relevant to a large num ber of experiments which measure switching in low capacitance JJs with sm all critical currents.^{15,16,17,18} W e show that by making the damping at high frequencies large enough, a favorable phase space topology for switching can be achieved.¹⁹ In this overdam ped situation the extemal phase can be treated classically and contributions ofm acroscopic quantum tunneling (MQT) to the switching probability can be neglected, in contrast to the underdam ped case.²⁰ Experim ental results are show n w here on-chip RC damping circuits are used to create an HFoverdam ped environm ent. We observe that for longer pulses of duration 20 µs, the switching process is initiated by therm al uctuations in the overdam ped system and therm al equilibrium is achieved at the base tem perature of the cryostat (25 mK). For short pulses of duration < 25 ns, the switching is una ected by therm al uctuations up to a temperature of 500 mK, and the width of the switching distribution at low tem peratures is rather determ ined by random variations in the repeated switch pulse. A though the detector apparently had the speed and sensitivity required for making a quantum m easurement, we were unfortunately unable to demonstrate quantum dynamics of the qubit due to problem s with uctuating background charges.

II. PHASE SPACE PORTRAITS

The non-linear dynamics of a DC -driven JJ can be pictorially represented in a phase space portrait. W e begin by examining the phase space portraits of the resistive and capacitively shunted junction (RCSJ), which is the simplest model from which we can gain intuitive understanding of the non-linear dynam ics. The RCSJ m odel consists of an ideal Josephson element of critical current I_0 biased at the current level I, which is shunted by the parallel plate capacitance of the tunnel junction, $C_{\rm J}$ and a resistor R , which m odels the dam ping at all frequencies (see g. 1 (a)). The circuit parameters de ne the two quantities $!_p =$ $I_0 = {}^{\prime}_0 C_J$ called the plasma frequency, and the quality factor $Q = !_{p} R C$. The dynam ics is classied as overdam ped or underdam ped for Q < 1 or Q > 1, respectively. Here $'_0 = h=2e$ is the reduced ux quantum .

The circuit dynam ics can be visualized by the motion of a particle of mass ${}^{2}_{0}C$ in a tilted washboard potential U () = E_{J} (i + cos) subjected to the damping force ${}^{2}_{0}$ =R, where the particle position corresponds to the phase di erence across the junction and the tilt i is the applied current normalized by the critical current, i = I=I₀ (see g 2(a)). Below the critical tilt i = 1 the ctitious particle will stay in a local minimum of the

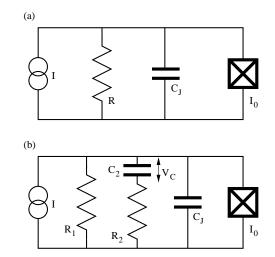


FIG.1: (a) RCSJ m odel of a Josephson junction. (b) Sim - ple m odel of a junction embedded in an environment with frequency dependent impedance.

washboard potential (marked A in g2(a)) corresponding to the superconducting state where V = h-i = 0. Increasing the tilt of the potential to i > 1, where local m in in a no longer exist, the particle will start to accelerate to a nite velocity $V = h_i > 0$ determ ined by the damping. If the tilt is then decreased below i = 1, the particle for an underdam ped JJ (Q > 1) will keep on m oving due to inertia. Further decreasing the tilt below the level i < ir, where loss per cycle from damping exceeds gain due to inertia, the particle will be retrapped in a localm in im um . In term softhe current-voltage characteristic, this corresponds to hysteresis, or a coexistence of two stable states, V = 0 and V > 0 for a bias xed in the region $i_r < i < 1$. For the overdam ped RCSJ m odel the particle will always be trapped in a local minimum fori 1 and freely evolving down the potential for i>1 and there is no coexistence of two stable states.

A phase space portrait^{19,21,22} of the RCSJ model is shown in g. 2 (b). This portrait shows trajectories that the particle would follow in the space of coordinate () versus velocity (-) for a few chosen initial conditions. The topology of the phase space portrait is characterized by several distinct features. F ix point attractors m arked \A " in g.2 correspond to the particle resting in a localm in im um of the washboard potential, and the saddle points marked \S" corresponds to the particle resting in an unstable state at the top of the potential barrier (com pare with g.2(a)). Two trajectories surrounding A and ending at S are the unstable trajectories which de ne the boundary of a basin of attraction: All initial conditions within this boundary will follow a trajectory leading to A.W e call this the O-basin of attraction. The thick line B is a stable lim iting cycle, corresponding to a freerunning state of the phase , where the circuit is undergoing Josephson oscillations with frequency $! = V = '_{0}$. All trajectories leading to the limiting cycle B start in

the 1-basin of attraction, which is the region outside the 0-basins. The existence of two basins of attraction in the phase space topology, and in particular the clear separation of all 0-basins by the 1-basin, m ake the underdam ped RCSJ circuit (Q > 1) appropriate for a sw itching current detector, as we discuss below. For the overdam ped RCSJ circuit (Q < 1) attractors A and B do not coexist for any xed bias condition, and it therefore can not be used for a sw itching current detector. How ever, the RCSJ m odel is not always the m ost realistic m odel for the dynam – ics of JJ circuits, as the dam ping in real experiments is usually frequency dependent, and in the case of sm all capacitance JJs, this frequency dependence can very m uch change the character of the dam ping.

At high frequencies of the order of the plasm a frequency of the junction (20-100 GHz for A 1/A 10 x/A 1 tunnel junctions) losses are typically due to radiation phenom ena, where the leads to the junction act as a wave quide for the m icrow ave radiation. If we m odel the leads as a transmission line, the high frequency impedance would correspond to a damping resistance of the order of free space in pedance Z $Z_0 = 2 = 60$. With the sm all capacitance of a typical JJ as used in present experim ents, this dam ping inevitably leads to overdam ped dynam ics Q < 1. It should be noted that for sm all capacitance JJs, underdam ped phase dynam ics is hard to achieve in practice as high impedance all the way up to the plasm a frequency is desired, and this requires an engineering e ort where the high im pedance leads need to be constructed very close to the junction.²³ How ever, at lower frequencies (typically below 10 M H z) the junction will see an impedance corresponding to the bias resistor R at the top of the cryostat, which can be chosen large enough to give Q > 1. The simplest circuit which captures the frequency dependence described above, is a JJ shunted by a series combination of a resistor R₂ and a capacitor C_2 in parallel with the resistor R_1 as shown in g.1(b). At high frequencies where C₂ is essentially a short, the circuit is described by the highfrequency quality factor $Q_1 = !_p R_{jj} C_J$, where R_{jj} is the parallel combination of R_1 and R_2 . At low frequencies where C₂ e ectively blocks, the quality factor reads $Q_0 = !_p R_1 C_J$. This model has been studied previously by several authors.^{15,19,24,25,26} Casting such a circuit in a m ore m athem atical language, it can be described by the coupled di erential equations^{19,25}

$$- = \frac{Q_1}{Q_0} - \frac{1}{E_J} \frac{dU()}{d} + v \frac{Q_0}{Q_1} - 1 + i_{n1} + i_{n2}$$
(1)
$$\underline{v} = \frac{Q_1}{Q_0^3} - \frac{1}{E_J} \frac{dU()}{d} + v + i_{n1} + i_{n2} \frac{Q_1^2}{Q_0(Q_0 - Q_1)} ;$$

where $v = V_C = R_1 I_0$ is the reduced voltage across C_2 and $= R_1 C_J = R_2 C_2$ rejects the value of the transition frequency, being ! $1=R_2 C_2$, between high- and lowim pedance regimes.

Phase space portraits for such a circuit are shown in gs. 2 (c) and (d). Here the y-axis shows the voltage v

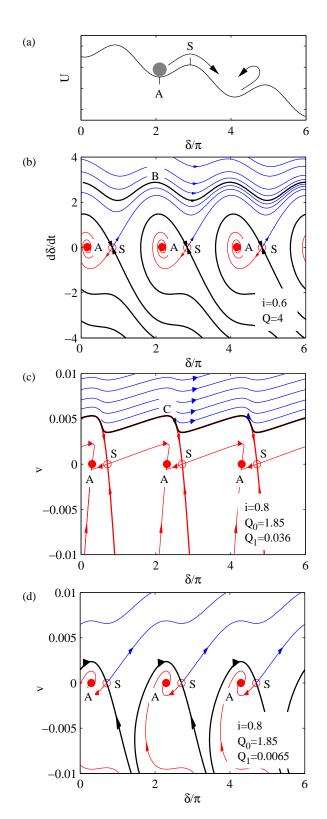


FIG.2: (Color online) (a) Tilted washboard model. (b) Underdam ped circuit biased at $i_r < i < 1$. (c) Circuit with frequency dependent dam ping and $Q_1 > Q_{1c}$ and with $Q_1 < Q_{1c}$ (d).

which is directly related to -. The topology of this phase portrait is also characterized by the coexistence of xpoints A and the limiting cycle B (not shown). However, for the parameters of g. 2 (c) (Q₀ = 1.85, Q₁ = 0.036 and i = 0.8.), the 0-basins and the 1-basin are now separated by an unstable limiting cycle C which does not intersect a saddle point. An initial condition which is in nitesim ally below or above C will eventually end up either in an attractor A, or on B respectively. In g. 2 (c) we also see that the boundaries of the 0-basins are directly touching one another as a consequence of the existence of C. Thus, it is possible to have a trajectory from one 0-basin to another 0-basin, without crossing the 1-basin.

This same HF-overdam pedm odelcan how everproduce a new topology by simply lowering the high-frequency quality factor Q₁. As we increase the high frequency damping, the unstable limiting cycle C slow ly approaches the saddle points S. For a critical value of Q₁ = Q_{1c}, C and S will touch and the phase-portrait suddenly changes its topology. Fig. 2 (d) shows the phase space portrait for Q₀ = 1.85, Q₁ = 0.0065 < Q_{1c} and i = 0.8 where we can see that C disappears and adjacent 0-state basins are again separated by the 1-basin { a topology of the same form as the underdam ped RCSJ m odel.

III. THE SW ITCH ING CURRENT DETECTOR

The transition from the 0-basin to the 1-basin, called switching, can be used as a very sensitive detector. The idea here is to choose a "hold" bias level and circuit param eters where the phase space portrait has a favorable topology such as that shown in gs. 2(b) and (d). A rapid "switch pulse" is applied to the circuit bringing the system from A to a point as close as possible to the unstable point S. Balanced at this unstable point, the circuit will be very sensitive to any external noise, or to the state of a qubit coupled to the circuit. The qubit state at the end of the switch pulse can be thought of as determ ining the initial condition, placing the ctitious phase particle on either side of the basin boundary, from which the particle will evolve to the respective attractor. The speed and accuracy of the measurement will depend on how rapidly the particle evolves away from the unstable point S, far enough in to the 0-basin or 1basin such that external noise can not drive the system to the other basin. From this discussion it is clear that a phase space portrait with the topology shown in q.2 (c) is not favorable for a switching current detector. Here the switching corresponds to crossing the unstable cycle C. Initial conditions which are in nitesimally close to C will remain close to C over many cycles of the phase, and thus a small amount of noise can kick the system back and forth between the 0-basins and the 1-basin, leading to a longer m easurem ent time and increased number of errors.

The measurement time is that time which is required

for the actual switching process to occur and must be shorter than the relaxation time of the qubit. In the ideal case the measurement time would be the same as the duration of the switch pulse. A much longer tim em ay be required to actually determ ine which basin the system has chosen. This longer detection time is the duration of the hold level needed to reach a signal to noise ratio larger than 1, which is in practice determ ine by the bandwidth of the low-noise amplier and lters in the second stage of the circuit. In our experim ents described in the following sections, we used a low noise amplier mounted at the top of the cryostat which has a very lim ited bandwidth and high input im pedance. W hile this am pli er has very low back action on the qubit circuit (very low current noise), it's low bandwidth increases the detection time such that individual measurem ents can be acquired only at < 10 kHz repetition rate. Since many measurements (10^4) are required to get good statistics when m easuring probabilities, the acquisition time window is some 0.5 seconds and the low frequency noise (drift or 1=f noise) in the biasing circuit will thus play a role in the detector accuracy.

IV. FLUCTUATIONS

The measurement time of a switching detector will depend on uctuations or noise in the circuit. The phase space portraits display the dissipative trajectories of a dynam ical system, but they do not contain any inform ation about the uctuations which necessarily accompany dissipation. For a switching current detector, we desire that these uctuations be as sm all as possible, and therefore the dissipative elements should be kept at as low a tem perature as possible. A nalyzing the switching current detector circuit with a therm alequilibrium model, we can calculate the rate of escape from the attractor A. This equilibrium escape rate how ever only sets an upper lim it. on the measurement time. When we apply the switch pulse, the goal is to bring the circuit out of equilibrium , and we desire that the sensitivity at the unstable point be large enough so that the measurem ent is made before equilibrium is achieved (i.e. before therm al uctuations drive the switching process).

Equilibrium uctuations can cause a JJ circuit to jump out of it's basin of attraction in a process know as thermalescape. The random force which gives rise to the escape trajectory will most likely take the system through the saddle point S, because such a trajectory would require a minimum of energy from the noise source.²¹ For the topology of phase space portraits shown in gs. 2 (b) and (d), therm al escape will result in a switching from a 0-basin to the 1-basin, with negligible probability of a "retrapping" event bringing the system back from the 1basin to a 0-basin. How ever, for the topology of g. 2 (c), therm allescape through the saddle point leads to another 0-basin, and thus the particle is im mediately retrapped in the next minimum of the washboard potential. This process of successive escape and retrapping is know as phase di usion, and it's signature is a non-zero DC voltage across the JJ circuit when biased below the critical current, i < 1.

Phase diusion can occur in the overdam ped RCSJ model, or in the HF-overdam ped model when param eters result in a phase space topology of g.2(c). In the latter case, a switching process can be identied which corresponds to the escape from a phase di usive state to the free running state, or to crossing the unstable lim iting cycle C in q.2(c) which marks the boundary between the phase di usive region and the 1-basin. This basin boundary C is form ed by the convergence of m any trajectories leading to di erent S, and the escape process of crossing this boundary is fundam entally di erent than escape from a O-basin to the 1-basin. Num erical simulations^{19,27,28} of switching in JJs with such a phase space topology show that escape over the unstable boundary C is characterized by late switching events, which arise because even a small amount of noise near this boundary can kick the system back and forth between the 1-basin and the many 0-basins for a long time before there is an actual escape leading to the limiting cycle B.

The rate of therm all escape from a 0-basin can be calculated using K ram ers' form $u \, a^{22,29,30}$

$$= \frac{!_{0}}{2} \exp(E = k_{B} T); \qquad (2)$$

with E being the depth of the potential well from A to $S_{r}k_{B}$ Boltzm ann's constant and T the tem perature. The prefactor $!_0=2$ is called the attempt frequency, where < 1 is a factor which depends on the damping. Analytical results for were found by K ramers in the two lim iting cases of underdam ped (Q > 1) and overdam ped (Q < 1) dynam ics. For the application of K ram ers' escape theory we require that E $k_{\rm B}T$, i.e. thermal escape is rare, so that each escape event is from a thermal equilibrium situation. The uctuations in thermal equilibrium are completely uncorrelated in time, which is to say that the strength of the uctuations are frequency independent (white noise). Furtherm ore, the Kramers form ula assum es absorbing boundary conditions, where the escape process which leads to a change of the basin of attraction has zero probability of return. These conditions restrict the direct application of K ram ers form ula in describing switching in JJ circuits³¹ to the case of the underdam ped RCSJm odelsuch as that depicted in g.2(b). In principle one could apply K ram ers form ula to the overdam ped RCSJ m odel, where the escape is from one well to the next well (switching between adjacent attractors A), but experiments thus far are unable to measure a single 2 jump of the phase, as this corresponds to an extrem ely sm all change in circuit energy.

Thermal induced switching of small capacitance Josephson junctions which experience frequency dependent damping as modeled by the circuit of Fig. 1 (b), was analyzed in experiment and theory by the Quantronics group^{15,26} who generalized K ram ers result. The theoretical analysis was subject to the constraint that the dynam – ics of the voltage across the shunt capacitor v is underdam ped (i.e. the quality factor $= R_2 R_{jj} C_2 I_0 = 0 (R_1 + R_2)$ 1 where R_{jj} is the parallel resistance of R_1 and R_2) so that the dynam ics of v is subject to the fast-time average e ects of the uctuating phase . Separating timescales in this way, the switching of v could then be regarded as an escape out of a meta-potential, B, form ed by the averaged uctuating force in the tilted washboard potential F = i hsin i v. A ssum ing non-absorbing boundary conditions, this "escape over a dissipation barrier" can be written as a generalization of K ram ers' form mula

$$= \frac{D(v_{t})}{2} \frac{F}{D} \frac{0}{v_{t}} \frac{F}{D} \exp(B): \quad (3)$$

Here D (v)_R is the position-dependent di usion constant, and B = $v_{b} = 0$)dv, where v_{b} and v_{t} stand for the bottom and the top of the e ective barrier, respectively. D etailed expressions can be found in refs.^{15,32}

In section V I, we use these escape rate formulas to analyze pulse and hold switching measurements. We demonstrate that long switching pulses lead to therm al equilibrium switching, whereas short pulses switch the circuit in a way that is independent of temperature at low temperatures, with the switching distribution determined by noise in the switch pulse rather than noise from the cooled dam ping circuit.

V. EXPERIMENTS

Experiments investigating junction current-voltage characteristics (IVC) as well as pulsed switching behavior were carried out in a dilution refrigerator with 25 m K base temperature. A block diagram of the measurement setup is shown in g. 3(a). A low noise instrumentation ampli er (Burr-Brown INA110, noise temperature 1:3 K at 10 kHz) is measuring the voltage across the sample while the sample is biased by a room temperature voltage source either via the bias capacitor C_b, or in series with a bias resistor R_b. The capacitor bias method was used for experiments with fast current pulses of duration $_{\rm p} = 25$ ns, while the conventional resistor bias method was well as for IVC measurements.

Three di erent samples are discussed in this paper which di er primarily in the range of the measured switching current (3 nA to 120 nA), and in the type of circuit used for the damping of the phase dynamics. These di erent damping circuits are labeled in the order in which they were in plemented, and are represented in g.3(a) as the blocks F_1 ; F_2 ; F_3 . These environments can be modeled as RC liters with di erent cut-o frequencies, as schematically be represented in g.3(b).

The key parameters for each sample are given in Table I. Sample I consisted of a Cooper pair transistor (CPT)

		СРТ			Shunt JJ			F ₁		F ₂		F ₃	
Sample	Туре	E _J =E _C	I ₀	$\mathtt{I}_{\mathtt{SW}}$	E J=E C	I ₀	$\mathtt{I}_{\mathtt{SW}}$	R ₁	C_1	R 2	C 2	R ₃	С 3
I	СРТ	32.9	58.5	3	-	-	-	60	1	-	-	-	-
II	СРТ	29	51.6	4.2	-	-	-	60	1	72	0.24	-	-
III	Q uantronium	2.2	21	12	30.3	158	120	1000	3	7,2	0.24	600	1.4

Currents are in [nA], resistances in [] and capacitances in [nF]

TABLE I: An overview over the parameters for the three di erent samples. Filter F_1 resembles the cryostat leads or a cold SM D lter. Filter F_2 is the on-chip damping circuit and F_3 is an on-chip RC - lter.

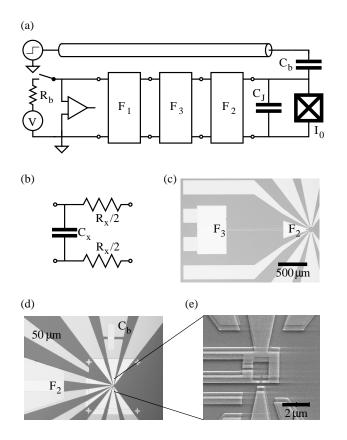


FIG. 3: (a) B lock diagram of the experimental setup. (b)
Schematic diagram of the model used to describes the three dierent lters F₁;F₂;F₃ which de ne the damping circuit.
(c) M icrograph of the sample showing the two on-chip RC lters F₁ and F₂. (d) M agnied view of the center part of the chip, F₂ and the bias capacitor. (e) E lectron m icroscope picture of the Q uantronium (sample III).

em bedded in an environm ent de ned solely by the twisted pair leads of the cryostat which is modeled as F_1 . Sam – ple II was a CPT fabricated in parallel with Sam ple I, having nearly identical parameters, di ering only in that sam ple II was embedded in a micro-fabricated on-chip HF-dam ping circuit F_2 . Sam ple III is a Quantronium¹ embedded in the sam e HF-dam ping F_2 used with sam – ple II, but with an additional micro-fabricated on-chip low-pass lter F_3 . The on-chip RC-environm ents F_2 and $\rm F_3$ used for samples II and III and the bias capacitor were fabricated with a two-step optical lithography process. The capacitors were actually two capacitors in series, form ed by a plasm a-oxidized Alground plane covered with a Au top plate. The top plates are connected to the rest of the circuit via resistors which are form ed from the same Au lm as the top plate, having a typical sheet resistance of 12 =2. The capacitors of F_3 could be measured quite accurately, from which we obtain a speci c capacitance of 13.6 fF/µm² that is used to determ ine all on-chip capacitors. Figure 3 (c) shows the essential parts of the chip and the components de ning the high-frequency environm ent. The bright rectangular area on the left side is the top plate of the capacitor, and the thin leads leading to the right are the resistors of

Iter F₃. Figure 3 (d) shows in detail the biasing capacitor C_b The bright trapezoidal area on the left is the top plate of the capacitor C₂ and the areas surrounded by dashed lines are damping resistors R₂=2. Figure 3 (e) is an electron m icroscope picture showing the A $1/A \ge 0_3/A 1$ tunnel junctions, which were fabricated in a third layer of electron beam lithography, with the standard two-angle evaporation through a shadow mask. Figure 3 (e) shows the quantronium circuit of sample III.

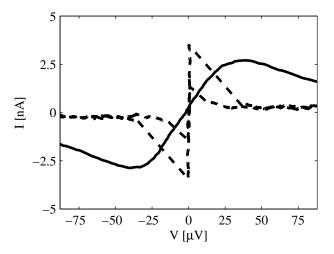


FIG.4: IV curves of sam ple I without designed RC environm ent (solid line) and of sam ple II with specially designed RC environm ent (dashed line).

The e ect of the on-chip HF damping from F_2 on the phase dynamics as can be seen in g. 4 where the IVC of sam ples I (solid line) and sam ple II (dashed line) are shown. These two CPT samples dieressentially by the presence of F_2 in sample II.W e see that the typical phase diusion shape of the IVC³³ of sample I is absent in sample II which shows a sharp supercurrent and hysteretic switching. The presence of the on-chip environment in sample II e ectively reduces phase di usion as can be explained by a phase-space topology as shown in qure 2(d). However, the very low value of I_{sw} is a direct indication of excessive noise in the circuit. Therefore the on-chip low-pass lter F₃ was in plemented in sam ple III, im proving the switching current to a value of 75% of the critical current. In the remainder of this paper we concentrate on investigating the switching behavior of sam ple III.

The ability to suppress phase di usion opens up the possibility to study fast switching with HF-overdam ped phase dynamics for the rst time. We used the pulse and hold m ethod to measure switching probabilities of sample III as a function of the amplitude of the switch pulse for two cases: A long pulse of 20 μ s where the switching was found to be controlled by equilibrium thermal escape, and a short pulse of 25ns, where the switching is clearly a non-equilibrium process.

The long pulses were form ed by applying a square voltage pulse through the bias resistor. The response to a simple square pulse is shown in g.5(a), where the applied voltage pulse is shown, and several scope traces of the measured voltage over the CPT are overlayed. Here we see that the switching causes an increase in the voltage over the sample which can occur at any time during the applied pulse. In order to do statistics we want to unambiguously count all switching events. Late switching events are di cult to distinguish from non-switching events as the voltage does not have tim e to rise above the noise level. W e can add a trailing hold level as shown in q. 5(b). This hold level and duration must be chosen so that there is zero probability of switching on the hold part of the pulse. The response to such a pulse shows that it is now easy to distinguish switch from non-switch events. In this case the hold level is used simply to quantize the output, and the switching which occurs during the initial switch pulse is found to be a therm al equilibrium escape process as discussed below .

The fast pulses were form ed with a new technique where a voltage waveform consisting of a sharp step followed by linear voltage rise is program med in to an arbitrary waveform generator. The slope on the sharp step $(dV=dt)_{pulse}$ is typically 6{7 times larger than the linear rise during the hold, $(dV=dt)_{hold}$. The voltage waveform is propagated to the chip through a coax cable having negligible dispersion for the sharp 25 ns voltage step used. A n on-chip bias capacitor C_b will dimension to give a sharp current pulse followed by a hold level, $I = C_b dV = dt$, which is shown in g.5(c). From the measured step amplitude needed to switch the junction

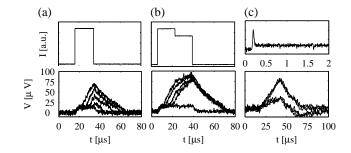


FIG. 5: (a) Square pulse and response. (b) Switch pulse with hold level and response. (c) Switch pulse with hold level and response, generated by the capacitive bias method. The nite voltage in the non-switch case is due to the series lter resistance and the two-point measurement setup.

and the value of $C_b = 1.4 \text{ pF}$, we calculate a pulse am plitude of 360 nA through C_b . Due to the symmetry of the lter stages F_1 to F_3 , only half of this 25 ns pulse current ow s through the junction, with the other half ow - ing through the lter to ground. Thus the peak current through the junction during the 25 ns pulse $I_p = 180 \text{ nA}$, which is larger than I_0 . Exceeding I_0 for this very short time is not unreasonable, bearing in m ind that the circuit is heavily overdam ped at high frequencies, and a strong kick will be needed to overcom e dam ping and bring the phase particle close to the saddle point.

The hold level for these fast pulses is 40 μ s,very much longer than the switch pulse, and its duration is set by the time needed for the response voltage to rise above the noise level. The rate of this voltage rise depends on the hold current level because after the switch we are essentially charging up the second stage liter and leads, F₃ and F₁, with the hold current, $I_{hold} = C_b (dV=dt)_{hold} = 56 nA$. For the low level of hold current used in these experiments, we can follow the voltage rise at the junction with the 100 kH z bandwidth low noise amplier at the top of the cryostat. Typically we turn o the hold current and reset the detector when the sam ple voltage is 30 μ V, so that the junction voltage is always well below the gap voltage V₂ = 400 μ V, and therefore quasi-particle dissipation during the hold can be neglected.

Pulsed switching measurements were performed were a sequence of 10^3 to 10^4 identical pulse-hold-reset cycles was applied to the sample while recording the voltage response of the sample. A threshold level was used to distinguish switching events (1) from non-switching events (0) as depicted in g. 6 (a). The maximum response voltage achieved during each cycle is found and a histogram of these values is plotted as seen in g. 6 (b). The hold level and duration are adjusted so as to achieve a bim odal distribution in the histogram, with zero events near the threshold level, meaning that there is zero am biguity in determining a switch event from a non-switch event. W e further check that the hold level itself, without the leading switch pulse, gives no switches of the sample. The sequence of switching events is stored as a binary sequence Y_i in temporal order. From this sequence we can calculate the switching probability,

$$P = \frac{1}{N} \sum_{i=1}^{X^{N}} Y_{i}$$
(4)

and the auto-correlation coe cients,

$$n_{k} = \frac{P_{N-k}}{\frac{1}{1}} \frac{(Y_{1}, \overline{Y})(Y_{1+k}, \overline{Y})}{P_{1}} \frac{(Y_{1}, \overline{Y})(Y_{1+k}, \overline{Y})}{(Y_{1}, \overline{Y})^{2}}$$
(5)

where k is the "lag" between pulses. The auto-correlation is a particularly important check for statistical independence of each switching event. A plot of r_k for k = 1:::1000 is shown in gure 6(c) and the random ness and low level of rk indicates that all switching events are not in uenced by any external periodic signal. W hen the circuit is not working properly, pick up of spurious signals up to the repetition frequency of the measurement, clearly shows up as a periodic modulation in the autocorrelation r_k . Of particular in portance is the correlation coe cient for lag one r_1 which tells how neighboring switching events in uence one another. Fig. 6(d) shows r_1 as a function of the wait time w between the end of the hold level and the start of the next switch pulse. For large values of $_{w}$, r_{1} uctuates around 0 not exceeding 0.05, which shows that any in uence of a switching or non-switching event on the following measurement, is statistically insigni cant. As $_{\rm w}$ is decreased how ever, a positive correlation is observed, with r_1 increasing exponentially with shorter w. Positive correlation indicates that a switching event (a "1") is more likely to be followed by another switching event. Fig. 6(d) shows a t to correlation r_1 to the function

$$r_1 = 3.345 \quad \exp \frac{w}{33.3\mu s}$$
 : (6)

We can extrapolate the t to the time $= 40.25 \, \mu s$ where the auto-correlation becom es $r_1 = 1$, m eaning that once the circuit switches it will always stay in the 1-state. In our experience, increasing the capacitance of $\operatorname{Iter} F_1$ causes to increase, from which we infer that the increase in the correlation r_1 for short w is resulting from errors where the detector is not properly reset because it does not have time to discharge the environment capacitance before a new pulse is applied. For the experiment shown in gure 6 the time constant of the environment was estimated to be 3 μ s. These observations indicate that it is necessary to bring the junction voltage very close to zero before the retrapping will occur, and the detector will reset. For good statistics many pulses are required and a short duty cycle is desirable in order to avoid e ects from low frequency noise as discussed section III. By studying the correlation coe cient r_1 in this way, we can choose an optim alduty cycle.

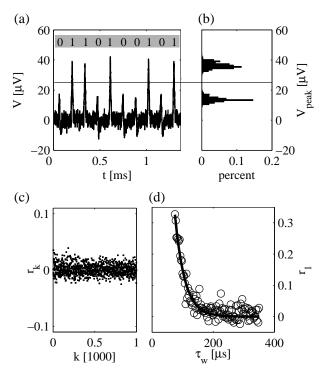


FIG.6: (a) Response of the sample to a pulse sequence resulting in switches (1) and no-switches (0) of the sample. (b) Peak voltage obtained during a current pulse, indicating good separation between the switch and non-switch signal. (c) Autocorrelation function r_k . (d) Correlation coe cient r_1 vs. the wait time, with tted exponential decay function.

VI. ANALYSIS

The switching probabilities were thus measured and the dependence on the amplitude of the switch pulse, P (I_p) was studied as as a function of temperature. Each measurement of P (I_p) began with a pulse sequences having pulse amplitude resulting in a switching probability P = 0, and the pulse amplitude was successively increased until P = 1. The measurement produces an "S-curve" as shown in gure 7, where the experimental data for the long pulse duration $_p = 20 \ \mu s$ is shown with crosses. The S-curves were taken at temperatures 100, 200, 300, 400 and 500 mK (right to left) respectively.

W e com pare the measured data to theoretical predictions based on them allescape as discussed in section IV. The lter F_1 causes a rounding of the applied square voltage pulse, which is accounted for by calculating the escape probability for a time dependent current³²,

$$P = 1 \quad \exp \quad \frac{1}{di=dt} \begin{bmatrix} Z_i \\ 0 \end{bmatrix} (i^0) di^0 \tag{7}$$

where the escape rate can be found using either eqns. 2 or 3. The simulated S-curves using eqn. 3 are plotted in gure 7 as solid lines for the temperatures corresponding to the measured data. Sample parameters

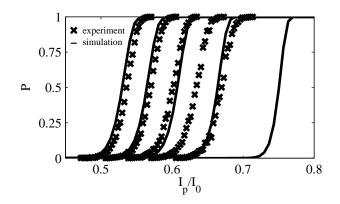


FIG. 7: Switching probability as a function of pulse height in the temperature range T = 100; 200; 300; 400; 500 mK (right to left) for a pulse duration $_{\rm p}$ = 20 µs. C rosses show m easured data and simulated data is shown as solid lines.

used for this calculation are the measured bias (including lter) resistance $R_1 = 11600$, the measured high frequency damping resistor, $R_2 = 72$, the high frequency dam ping capacitance $C_2 = 0.207 \text{ nF}$, the junction capacitance $C_J = 30$ fF, and the calculated critical current $I_0 = 148 \text{ nA}$. The critical current $I_0 = 148 \text{ nA}$ is not the bare critical current $I_0 = 158 \text{ nA}$ since the quantronium was biased at a magnetic eld such that a persistent current of 10 nA was owing in the bop. These param eters are all independently determ ined, and not adjusted to improve the t. However, the capacitance of $lter F_1$ was uncertain, having a nom inal value of 10nF, and unknown tem perature dependence below 4 K. Cooling the sam e capacitance to 4 K, we observed a decrease of C₁ by around 10%. This capacitor C1 determ ines the rounding of the square voltage pulse, and thus the time dependence of the current applied to the junction. W e found that it was necessary to assume $C_1 = 3 \text{ nF}$ in order for the simulations to agree with experiment. This low value of C1 at low tem peratures is not unreasonable, as circuit simulations with the nom inalvalue of 10 nF showed that the initial pulse would not exceed the hold level, which clearly is not possible because excellent latching of the circuit was observed.

From the experim ental and simulated S-curves, we dene the switching current of the sample as the pulse am plitude that gives 50 % switching P (I_{sw}) = 0.5 and the resolution is de ned from the S-curve by $I = I_p (P =$ $\downarrow (P = 0:1)$. A comparison of experimental and 0:9) theoretical I_{sw} vs. T and I=I $_{\text{sw}}$ vs. T is shown in g.8. We see that the experim ental data for the long pulses (points marked by an X) are in reasonably good agreem ent with the simulated values when the theory of switching in an environment with frequency dependent damping is used (escape from a meta-potential, equation 3) which is plotted as a solid line in g. 8(a). We note that for the 20 µs pulses, escape occurs at bias currents i 0:7, where the phase space has a topology as shown in gure 2 (d). Hence we can neglect phase di usion and

escape is from a saddle point, so that the non-absorbing boundary condition assumed in the theory is valid. For com parison, we use the overdam ped K ram ers form ula (equation 2) to simulate the S-curve and calculate I_{sw} and I, which is shown by the dashed line in g. 8. Here the prefactor (Q) is given in ref.²⁵ and we have used the high frequency quality factor $Q_1 = 0.027$ as determ ined by the resistor R_2 only. We see that the K ram ers formula overestimates I_{sw} by some 25% (g. 8(a)) and is worse than the simulation based on eqn. 3, in reproducing the tem perature dependence of I (g. 8(b)). In fact, the experimental data for the 20 µs pulses only shows a weak increase in I over the tem perature range studied, whereas both theoretical curves predict a slight increase in I. Thus an equilibrium therm all escape model explains the data for long, 20 µs pulses reasonably well and the data is better explained by the theory of escape with frequency dependent dam ping, than by the sim pler theory embodied in the overdam ped K ram ers form ula. However the correspondence with the former theory is not perfect. W e m ay explain these deviations as being due to the fact that the quality factor = 4:49 (see section IV) does not really satisfy the condition for validity of the theory, 1.

Experimental data for the short pulses of duration $_{p}$ = 25 ns generated by the capacitive bias method is plotted in g. 8 as circles. Here we see that the value of I_{sw} is constant in the tem perature range studied, indicating that escape is not from a therm al equilibrium state. For the ideal phase space topology, as shown in gure 2(d), the initial pulse would bring the phase particle arbitrarily close to the saddle point S for the hold bias level. If the separation in to the basins of attraction occurs before therm al equilibrium can be established, we would not expect tem perature dependence of I_{sw} . In this case, the width of the switching distribution will be determ ined not by therm al uctuations, but by other sources of noise, such as random variation in the height of the switch pulse. These variations are signi cant because the 1/f noise from the waveform generator must be taken in to account when generating the train of pulses over the time window of the measurement which was about 0.5 sec. In our experiments however, we may not have achieved a constant hold level since the voltage ramp from the waveform generator is not perfectly sm ooth. K now ing the bias capacitor we can calculate an average hold level of $i_{hold} = 0.35$, som ew hat low er than the critical value of $i_{hold} = 0.67$ necessary to achieve the phase space topology of gure 2(d). Nevertheless, we observe excellent latching of the circuit for these 25 ns switch pulses. We conclude that the observed tem perature independence of I_{sw} , and the fact that $I_{sw}\ exceeds$ Io by 20% is consistent with a very rapid switching of the junction.

W e can rule out excessive therm alonise as a reason for the tem perature independent value of I_{sw} for the short pulses. By measuring the gate voltage dependence of I_{sw} as a function of the tem perature, a clear transition from

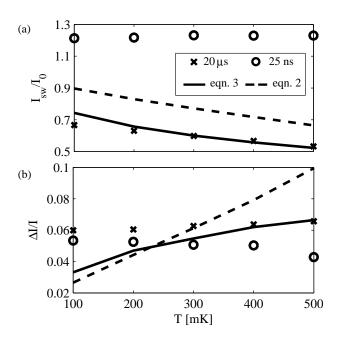


FIG. 8: Switching current nom alized to critical current (a) and relative resolution (b) of sam ple III.C rosses indicate measured values for $_{\rm p}$ = 20 µs, solid and dashed lines are calculated values using a generalization of K ram ers' large friction result and K ram ers' original result, respectively. C incles are m easured values for $_{\rm p}$ = 25 ns.

2e to e periodicity was observed in the tem perature range 250 m K to 300 m K.For the size of the superconducting island used in this experiment, we can estimate a crossover tem perature T 300 m K, above which the free energy di erence between even and odd parity goes to zero.³⁴ H ence, we know that the sample is in equilibrium with the therm on eter below T, and therefore heating e ects that m ight occur in the short pulse experiments, can not explain the fact that the observed $I_{\rm sw}$ is independent of tem perature.

Thus we have achieved a very rapid, 25 ns m easurement time of the switching current, which should be su – cient form easurement of the quantum state of a quantronium circuit. For qubit readout, not only the measurement time is important, but also the resolution of the detector. For the 25 ns pulse, we obtained the resolution of I=I $_{sw}$ = 0.055, or I = 9.9 nA. This implies that single shot readout is possible for a Quantronium with parameters E_c = 0.5 K and $E_J = E_c$ = 2.5 where the

sw itching current of the two qubit states at the optim al readout point di er by 9.6 nA. Num erous experim ents were m ade with m icrowave pulses and continuous m icrowave radiation to try and nd the qubit resonance. However, due in part to uncertainty in the qubit circuit param eters (level separation) and in part to jumps in background charge, no qubit resonance was detected in these experim ents.

VII. CONCLUSION

Fast and sensitive measurement of the switching current can be achieved with a pulse-and-hold m easurem ent m ethod, where an initial switch pulse brings the JJ circuit close to an unstable point in the phase space of the circuit biased at the hold level. This technique exploits the in nite sensitivity of a non-linear dynam ical system at a point of bifurcation, a common theme in m any successful JJ qubit detectors. W e have shown that with properly designed frequency dependent damping, fast switching can be achieved even when the high frequency dynam ics of the JJ circuit are overdam ped. W ith an on-chip RC dam ping circuit, we have experim entally studied the therm alescape process in overdam ped JJs. A capacitor biasm ethod was used to create very rapid 25ns switch pulses. We demonstrated fast switching in such overdam ped JJs for the st time, where the switching was not described by them al equilibrium escape. The m ethods presented here are a simple and inexpensive way to perform sensitive switching current measurements in Josephson junction circuits. W hile we have shown that the sensitivity can be high, the e ect of back-action of such a detector is still unclear and might be a reason why no quantum e ects were observed. In contrast to the readout strategy presented here, all other working qubit-readout strategies, both static switching and dispersive, are based on underdam ped phase dynam ics.

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